

Reg. No.

MANIPAL UNIVERSITY, MANIPAL III SEMESTER M.Sc. PHYSICS

Parpared by

SUBJECT: CONDENSED MATTER PHYSICS I - PHY 707.1 (REVISED CREDIT SYSTEM)

Time 3 Hrs.]	(01-12-2016)	[Max. Marks: 50
Note:	Answer ANY FIVE FULL questions in a continuous sequence.	
1A. Assuming	a point source, derive an expression for the thickness of the deposit al	long a planar substrate. [5]
1B. Discuss the	following deposition techniques (a) rf sputtering (b) anodic oxidatio	on [5]
2A. Explain the	e quartz crystal monitoring technique and discuss the sensitivity of the	e oscillator. [6]
0.150 mm	equal thickness are formed in a Fizeau technique with the fringes sep. The fringes at the step gets shifted by an amount 0.025 mm. If a man 589.3 nm is used, calculate the thickness of the deposited layer.	parated at a distance of nonochromatic source of [2]
2C. Calculate t	the contact angle for the following condition: Substrate to vapor interface between film-substrate and vapor-film interfacial energy.	facial energy is equal to [2]
	expression for heterogeneous nucleation rate equation using capillarion in the state of the stat	ty model. [8]
4A. Discuss the expression	ne influence of surface scattering on the conductivity of continuous the for the electrical conductivity.	in films and derive an [5]
4B. Derive an metal thin	expression for temperature coefficient of resistivity and strain sensitin films.	ivity of a discontinuous [5]
Using the light from	method of summation, derive an expression for the irradiance of a single layer homogenous non absorbing thin film in air.	reflected and transmitted
	hotolithography? Explain various steps involved in obtaining the nand and negative photoresists.	ostructures using [4
6B. Explain in	nert gas condensation process for creating nano materials.	[4
6C. Mention	few applications of nano materials.	[2

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